

# MOSFET – Dual, N-Channel, POWERTRENCH®

30 V, 10 m $\Omega$ , 20 m $\Omega$ 

# **FDMC8200S**

#### **General Description**

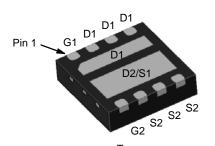
This device includes two specialized N-Channel MOSFETs in a dual Power33 (3 mm x 3 mm MLP) package. The switch node has been internally connected to enable easy placement and routing of synchronous buck converters. The control MOSFET (Q1) and synchronous MOSFET (Q2) have been designed to provide optimal power efficiency.

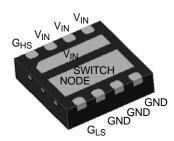
#### **Features**

- Q1: N-Channel
  - Max  $r_{DS(on)} = 20 \text{ m}\Omega$  at  $V_{GS} = 10 \text{ V}$ ,  $I_D = 6 \text{ A}$
  - Max  $r_{DS(on)} = 32 \text{ m}\Omega$  at  $V_{GS} = 4.5 \text{ V}$ ,  $I_D = 5 \text{ A}$
- Q2: N-Channel
  - Max  $r_{DS(on)} = 10 \text{ m}\Omega$  at  $V_{GS} = 10 \text{ V}$ ,  $I_D = 8.5 \text{ A}$
  - Max  $r_{DS(on)} = 13.5 \text{ m}\Omega$  at  $V_{GS} = 4.5 \text{ V}$ ,  $I_D = 7.2 \text{ A}$
- This Device is Pb-Free, Halide Free and is RoHS Compliant

#### **Applications**

- Mobile Computing
- Mobile Internet Devices
- General Purpose Point of Load





WDFN8 3x3, 0.65P (Power 33) CASE 511DE

**Bottom** 

#### **MARKING DIAGRAM**

\$Y&Z&2&K FDMC 8200S

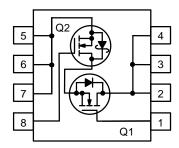
\$Y = Logo

&Z = Assembly Plant Code &2 = 2-Digit Date Code

&K = 2-Digits Lot Run Traceability Code

FDMC8200S = Device Code

#### **SCHEMATIC**



#### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 10 of this data sheet.

## **MOSFET MAXIMUM RATINGS** ( $T_C = 25^{\circ}C$ , unless otherwise noted)

Symbol	Parameter	Q1	Q2	Unit
$V_{DS}$	Drain to Source Voltage	30	30	V
$V_{GS}$	Gate to Source Voltage (Note 4	±20	±20	V
Ι <sub>D</sub>	Drain Current - Continuous (Package Limited) T <sub>C</sub> = 25°C	18	13	Α
	<ul> <li>Continuous (Silicon Limited) T<sub>C</sub> = 25°C</li> </ul>	23	46	
	– Continuous $T_A = 25^{\circ}C$	6 (Note 1a)	8.5 (Note 1b)	
	– Pulsed	40	27	
E <sub>AS</sub>	Single Pulse Avalanche Energy (Note 3	12	32	
$P_{D}$	Power Dissipation for Single Operation T <sub>A</sub> = 25°C	1.9 (Note 1a)	2.5 (Note 1b)	W
	Power Dissipation for Single Operation $T_A = 25^{\circ}C$	0.7 (Note 1c)	1.0 (Note 1d)	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range	-55 to	+150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

# **THERMAL CHARACTERISTICS** ( $T_C = 25^{\circ}C$ , unless otherwise noted)

Symbol	Parameter	Q1	Q2	Unit
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	65 (Note 1a)	50 (Note 1b)	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	180 (Note 1c)	125 (Note 1d)	
$R_{\theta JC}$	Thermal Resistance, Junction to Case	7.5	4.2	

## **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Unit	
OFF CHARACTERISTICS								
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	n to Source Breakdown Voltage $I_D = 250 \mu A, V_{GS} = 0 \text{ V}$ $I_D = 1 \text{ mA}, V_{GS} = 0 \text{ V}$		30 30	_	- -	V	
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25°C $I_D$ = 1 mA, referenced to 25°C	Q1 Q2	_ _	14 13	- -	mV/°C	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V	Q1 Q2	- -	_	1 500	μΑ	
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	Q1 Q2	_ _	_	100 100	nA	
ON CHARA	CTERISTICS							
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$ $V_{GS} = V_{DS}, I_D = 1 \text{ mA}$	Q1 Q2	1.0 1.0	2.3 2.0	3.0 3.0	V	
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = 250 μA, referenced to 25°C $I_D$ = 1 mA, referenced to 25°C	Q1 Q2	- -	-5 -6	- -	mV/°C	
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V, } I_D = 6 \text{ A}$ $V_{GS} = 4.5 \text{ V, } I_D = 5 \text{ A}$ $V_{GS} = 10 \text{ V, } I_D = 6 \text{ A, } T_J = 125^{\circ}\text{C}$	Q1	- - -	16 24 22	20 32 28	mΩ	
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 8.5 A V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 7.2 A V <sub>GS</sub> = 10 V, I <sub>D</sub> = 8.5 A, T <sub>J</sub> = 125°C	Q2	- - -	7.8 10.3 11.4	10.0 13.5 13.1		
9FS	Forward Transconductance	$V_{DD} = 5 \text{ V}, I_{D} = 6 \text{ A}$ $V_{DD} = 5 \text{ V}, I_{D} = 8.5 \text{ A}$	Q1 Q2	_ _	29 43	1 1	S	
DYNAMIC CHARACTERISTICS								
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHZ}$	Q1 Q2	_ _	495 1080	660 1436	pF	
C <sub>oss</sub>	Output Capacitance		Q1 Q2	_ _	145 373	195 495	pF	
C <sub>rss</sub>	Reverse Transfer Capacitance		Q1 Q2	- -	20 35	30 52	pF	

## **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise noted) (continued)

Symbol	Parameter	Test Conditions	Type	Min	Тур	Max	Unit
DYNAMIC (	CHARACTERISTICS	•					
R <sub>g</sub>	Gate Resistance	f = 1 MHz	Q1 Q2	0.2 0.2	1.4 1.2	4.2 3.6	Ω
SWITCHING	G CHARACTERISTICS						
t <sub>d(on)</sub>	Turn-On Delay Time	Q1 V <sub>DD</sub> = 15 V, I <sub>D</sub> = 1 A, V <sub>GS</sub> = 10 V,	Q1 Q2	_ _	11 7.6	20 15	ns
t <sub>r</sub>	Rise Time	$R_{GEN} = 6 \Omega$ $Q2$ $V_{DD} = 15 \text{ V, } I_{D} = 1 \text{ A, } V_{GS} = 10 \text{ V,}$	Q1 Q2	-	3.1 1.8	10 10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_{GEN} = 6 \Omega$	Q1 Q2	- -	35 21	56 34	ns
t <sub>f</sub>	Fall Time		Q1 Q2	_ _	1.3 8.5	10 17	ns
Q <sub>g(TOT)</sub>	Total Gate Charge	$V_{GS} = 0 \text{ V to } 10 \text{ V}$ Q1 $V_{DD} = 15 \text{ V}, I_{D} = 6 \text{ A}$ Q2 $V_{DD} = 15 \text{ V}, I_{D} = 8.5 \text{ A}$	Q1 Q2	- -	7.3 15.7	10 22	nC
Q <sub>g(TOT)</sub>	Total Gate Charge	$V_{GS} = 0 \text{ V to } 4.5 \text{ V}$ Q1 $V_{DD} = 15 \text{ V}, I_D = 6 \text{ A}$ Q2 $V_{DD} = 15 \text{ V}, I_D = 8.5 \text{ A}$	Q1 Q2	- -	3.1 7.2	4.3 10	nC
$Q_{gs}$	Gate to Source Charge	Q1 V <sub>DD</sub> = 15 V, I <sub>D</sub> = 6 A	Q1 Q2	- -	1.8 3	- -	nC
$Q_{gd}$	Gate to Drain "Miller" Charge	Q2 V <sub>DD</sub> = 15 V, I <sub>D</sub> = 8.5 A	Q1 Q2	_ _	1 1.9	_ _	nC
DRAIN-SO	URCE CHARACTERISTICS						
V <sub>SD</sub>	Source-Drain Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 6 A (Note 2) V <sub>GS</sub> = 0 V, I <sub>S</sub> = 8.5 A (Note 2) V <sub>GS</sub> = 0 V, I <sub>S</sub> = 1.3 A (Note 2)	Q1 Q2 Q2	_ _	0.8 0.8 0.6	1.2 1.2 0.8	V
t <sub>rr</sub>	Reverse Recovery Time	Q1 I <sub>F</sub> = 6 A, di/dt = 100 A/μS	Q1 Q2	_ _	13 20	24 32	ns
Q <sub>rr</sub>	Reverse Recovery Charge	Q2 I <sub>F</sub> = 8.5 A, di/dt = 300 A/μS	Q1 Q2	- -	2.3 15	10 24	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

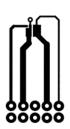
1. R<sub>θJA</sub> is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR–4 material. R<sub>θJC</sub> is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.



a. 65°C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper



b. 50°C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper



c.  $180^{\circ}\text{C/W}$  when mounted on a minimum pad of 2 oz copper



d. 125°C/W when mounted on a minimum pad of 2 oz copper

- 2. Pulse Test: Pulse Width < 300  $\mu$ s, Duty cycle < 2.0%. 3. Starting Q1: T = 25°C, L = 1 mH, I = 5 A, Vgs = 10 V, Vdd = 27 V, 100% test at L = 3 mH, I = 4 A; Q2: T = 25°C, L = 1 mH, I = 8 A, Vgs = 10 V, Vdd = 27 V, 100% test at L = 3 mH, I = 3.2 A.
- 4. As an N-ch device, the negative Vgs rating is for low duty cycle pulse occurrence only. No continuous rating is implied.

#### TYPICAL CHARACTERISTICS (Q1 N-CHANNEL) (T<sub>.1</sub> = 25°C, unless otherwise noted)

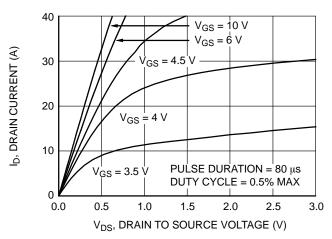


Figure 1. On Region Characteristics

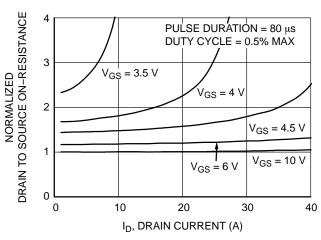


Figure 2. Normalized On–Resistance vs.

Drain Current and Gate Voltage

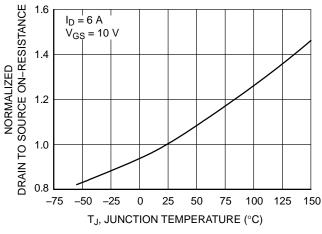


Figure 3. Normalized On Resistance vs. Junction Temperature

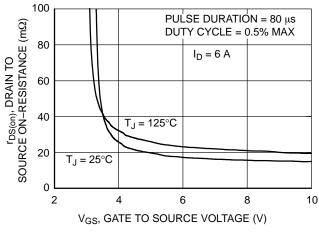


Figure 4. On-Resistance vs. Gate to Source Voltage

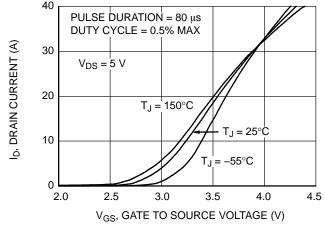


Figure 5. Transfer Characteristics

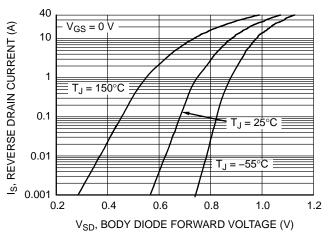


Figure 6. Source to Drain Diode Forward Voltage vs.
Source Current

## TYPICAL CHARACTERISTICS (Q1 N-CHANNEL) (T<sub>J</sub> = 25°C, unless otherwise noted) (continued)

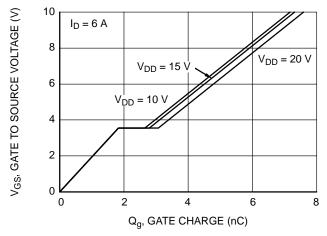


Figure 7. Gate Charge Characteristics

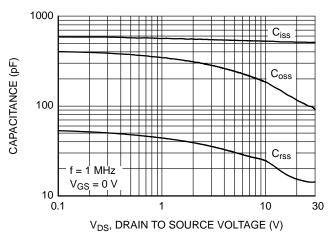


Figure 8. Capacitance vs. Drain to Source Voltage

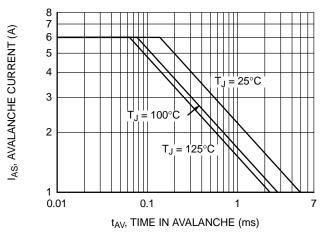


Figure 9. Unclamped Inductive Switching Capability

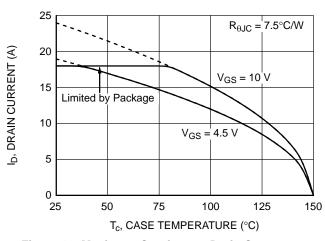


Figure 10. Maximum Continuous Drain Current vs.

Case Temperature

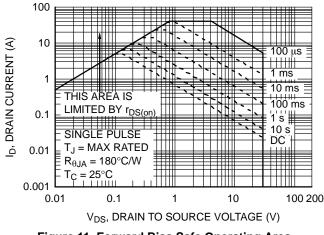


Figure 11. Forward Bias Safe Operating Area

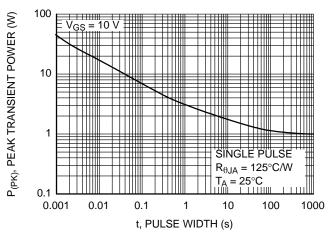


Figure 12. Single Pulse Maximum Power Dissipation

# TYPICAL CHARACTERISTICS (Q1 N-CHANNEL) ( $T_J = 25$ °C, unless otherwise noted) (continued)

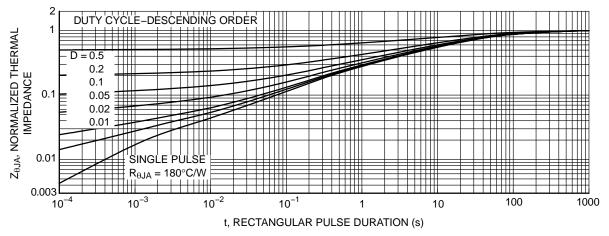


Figure 13. Junction-to-Ambient Transient Thermal Response Curve

#### TYPICAL CHARACTERISTICS (Q2 N-CHANNEL) (T, = 25°C, unless otherwise noted)

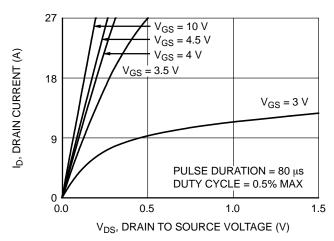


Figure 14. On-Region Characteristics

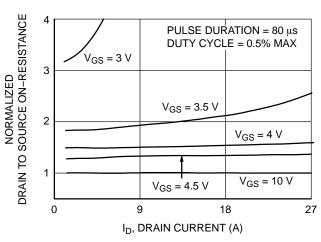


Figure 15. Normalized On–Resistance vs.

Drain Current and Gate Voltage

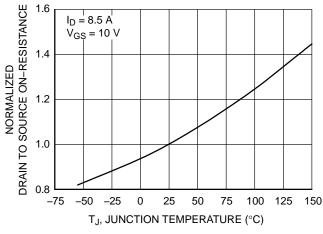


Figure 16. Normalized On–Resistance vs. Junction Temperature

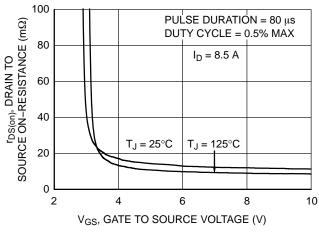


Figure 17. On-Resistance vs. Gate to Source Voltage

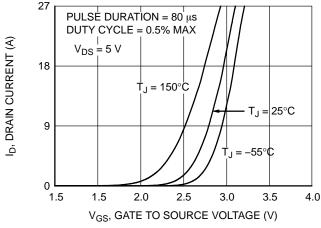


Figure 18. Transfer Characteristics

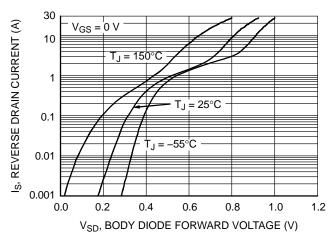


Figure 19. Source to Drain Diode Forward Voltage vs.
Source Current

# 

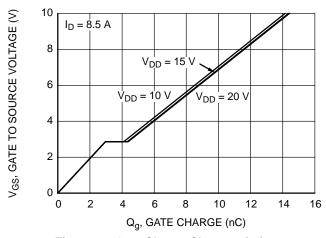


Figure 20. Gate Charge Characteristics

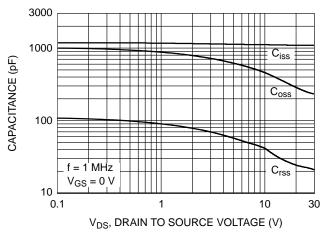


Figure 21. Capacitance vs. Drain to Source Voltage

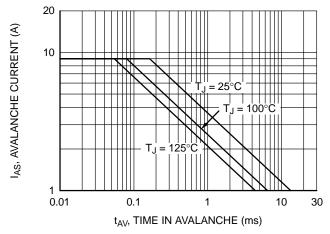


Figure 22. Unclamped Inductive Switching Capability

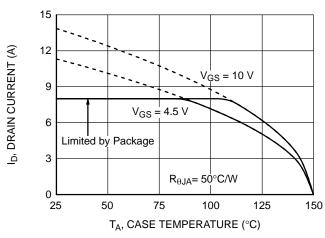


Figure 23. Maximum Continuous Drain Current vs.

Case Temperature

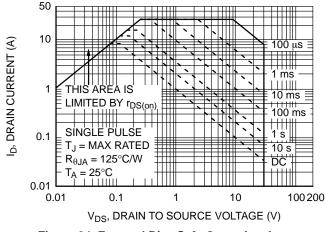


Figure 24. Forward Bias Safe Operating Area

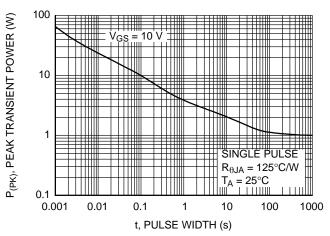


Figure 25. Single Pulse Maximum Power Dissipation

# TYPICAL CHARACTERISTICS (Q2 N-CHANNEL) ( $T_J = 25$ °C, unless otherwise noted) (continued)

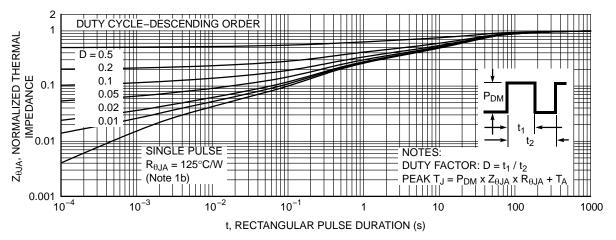


Figure 26. Junction-to-Ambient Transient Thermal Response Curve

#### TYPICAL CHARACTERISTICS (continued)

#### **SyncFET Schottky Body Diode Characteristics**

onsemi's SyncFET™ process embeds a Schottky diode in parallel with POWERTRENCH MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 14 shows the reverses recovery characteristic of the FDMC8200S.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

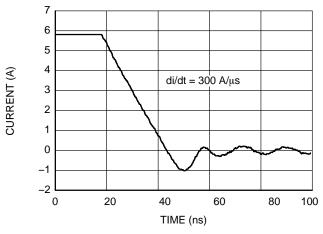


Figure 27. FDMC8200S SyncFET Body Diode Reverse Recovery Characteristic

Figure 28. SyncFET Body Diode Reverses Leakage Versus Drain-Source Voltage

#### PACKAGE MARKING AND ORDERING INFORMATION

Device	Device Marking	Package	Reel Size	Tape Width	Shipping <sup>†</sup>
FDMC8200S	FDMC8200S	WDFN8 3x3, 0.65P (Power 33) (Pb–Free, Halide Free)	13"	12 mm	3000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

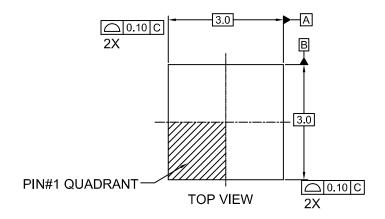
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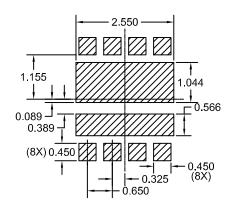
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#### WDFN8 3x3, 0.65P CASE 511DE ISSUE O

**DATE 31 AUG 2016** 



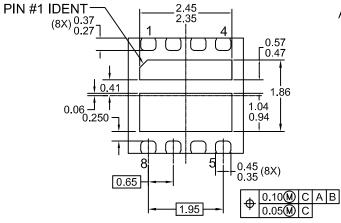


0.8 MAX // 0.10 C 0.08 C 8:85 SEATING SIDE VIEW

RECOMMENDED LAND PATTERN

## NOTES:

- A. DOES NOT CONFORM TO JEDEC REGISTRATION MO-229
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994



**BOTTOM VIEW** 

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